Application No.: 10/006,704 Docket No.: M4065.0369/P369-A

STATUS OF THE CLAIMS

Claims 1-25 (Canceled).

26. (Previously presented) A composition suitable for use in etching an

insulative layer formed over a substrate in a semiconductor device, said composition

consisting of:

a flowing plasma etchant mixture consisting of at least one fluorocarbon and

ammonia, wherein said at least one fluorocarbon and ammonia form a reactive mixture.

27. (Previously presented) The composition of claim 26, wherein said

fluorocarbon is at least one member selected from the group consisting of

fluorohydrocarbons, chlorofluorocarbons and chlorofluorohydrocarbons.

28. (Original) The composition of claim 27, wherein said fluorocarbon is at

least one member selected from the group consisting of C₄F₈, C₄F₆, C₅F₈, CF₄, C₂F₆, C₃F₈,

CHF₃, and CH₂F₂.

29. (Original) The composition of claim 26, wherein said fluorocarbon is at

least one member selected from the group consisting of CF₄, CHF₃, and CH₂F₂.

30. (Original) The composition of claim 29, wherein said fluorocarbon is at

least two members selected from the group consisting of CF₄, CHF₃, and CH₂F₂.

31. (Original) The composition of claim 30, wherein said fluorocarbon is a

combination of CF₄, CHF₃, and CH₂F₂.

2

Application No.: 10/006,704 Docket No.: M4065.0369/P369-A

32. (Previously presented) The composition of claim 26, wherein said composition is ineffective to remove side wall spacers of a gate stack formed over said substrate.

Claims 33-70 (Canceled).

71. (Previously presented) A composition suitable for use in etching an insulative layer formed on a substrate in a semiconductor device, said composition consisting of:

a plasma etchant mixture consisting of CF4, at least one other fluorocarbon, and NH3, wherein said CF4, at least one other fluorocarbon, and NH3 form a reactive mixture.

Claims 72-76 (Canceled).

77. (Previously presented) A composition suitable for use in etching an insulative layer formed over a substrate in a semiconductor device, said composition consisting of:

a gaseous etchant mixture consisting of at least one fluorocarbon and ammonia, wherein said at least one fluorocarbon and ammonia form a reactive mixture.